

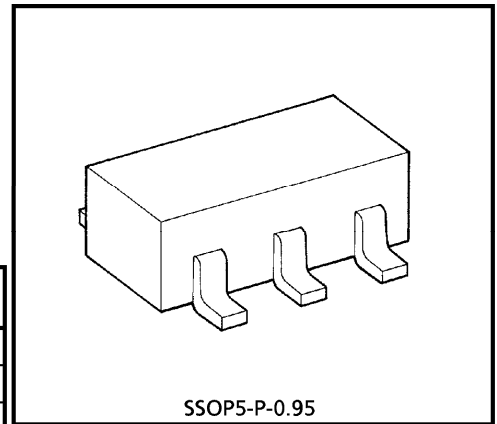
TC4S11F

2 INPUT NAND GATE

The TC4S11F is 2-input positive logic NAND gates. Gate output with inverter buffer improve the input-output characteristics and even if the load capacitance increases, it can be stopped the change of propagation time.

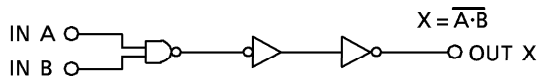
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V _{DD}	V _{SS} - 0.5~V _{SS} + 20	V
Input Voltage	V _{IN}	V _{SS} - 0.5~V _{DD} + 0.5	V
Output Voltage	V _{OUT}	V _{SS} - 0.5~V _{DD} + 0.5	V
DC Input Current	I _{IN}	± 10	mA
Power Dissipation	P _D	200	mW
Operating Temperature Range	T _{opr}	- 40~85	°C
Storage Temperature Range	T _{stg}	- 65~150	°C
Lead Temperature (10s)	T _L	260	°C

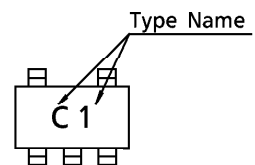


SSOP5-P-0.95
Weight : 0.016g (Typ.)

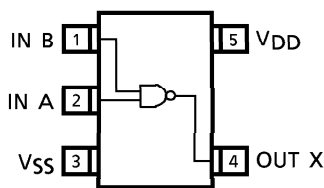
LOGIC DIAGRAM



MARKING



PIN CONFIGURATION (TOP VIEW)



RECOMMENDED OPERATING CONDITIONS (V_{SS} = 0V)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	
DC Supply Voltage	V _{DD}	—	3	—	18	V
Input Voltage	V _{IN}	—	0	—	V _{DD}	V

STATIC ELECTRICAL CHARACTERISTICS (V_{SS} = 0V)

CHARACTERISTIC	SYM-BOL	TEST CONDITION	V _{DD} (V)	- 40°C		25°C			85°C		UNIT	
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.		
High-Level Output Voltage	V _{OH}	I _{OUT} < 1μA V _{IN} = V _{SS} , V _{DD}	5	4.95	—	4.95	5.00	—	4.95	—	V	
			10	9.95	—	9.95	10.00	—	9.95	—		
			15	14.95	—	14.95	15.00	—	14.95	—		
Low-Level Output Voltage	V _{OL}	I _{OUT} < 1μA V _{IN} = V _{DD}	5	—	0.05	—	0.00	0.05	—	0.05	V	
			10	—	0.05	—	0.00	0.05	—	0.05		
			15	—	0.05	—	0.00	0.05	—	0.05		
Output High Current	I _{OH}	V _{OH} = 4.6V V _{OH} = 2.5V V _{OH} = 9.5V V _{OH} = 13.5V V _{IN} = V _{SS} , V _{DD}	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA	
			5	-2.5	—	-2.1	-4.0	—	-1.7	—		
			10	-1.5	—	-1.3	-2.2	—	-1.1	—		
			15	-4.0	—	-3.4	-9.0	—	-2.8	—		
Output Low Current	I _{OL}	V _{OL} = 0.4V V _{OL} = 0.5V V _{OL} = 1.5V V _{IN} = V _{DD}	5	0.61	—	0.51	1.2	—	0.42	—	mA	
			10	1.5	—	1.3	3.2	—	1.1	—		
			15	4.0	—	3.4	12.0	—	2.8	—		
			5	3.5	—	3.5	2.75	—	3.5	—		
Input High Voltage	V _{IH}	V _{OUT} = 0.5V, 4.5V V _{OUT} = 1.0V, 9.0V V _{OUT} = 1.5V, 13.5V I _{OUT} < 1μA	10	7.0	—	7.0	5.5	—	7.0	—	V	
			15	11.0	—	11.0	8.25	—	11.0	—		
			5	—	1.5	—	2.25	1.5	—	1.5		—
Input Low Voltage	V _{IL}	V _{OUT} = 4.5V V _{OUT} = 9.0V V _{OUT} = 13.5V I _{OUT} < 1μA	10	—	3.0	—	4.5	3.0	—	3.0	V	
			15	—	4.0	—	6.75	4.0	—	4.0		
			5	—	—	—	—	—	—	—		—
Input Current	H Level	I _{IH}	V _{IH} = 18V	18	—	0.1	—	10 ⁻⁵	0.1	—	1.0	μA
	L Level	I _{IL}	V _{IL} = 0V	18	—	-0.1	—	-10 ⁻⁵	-0.1	—	-1.0	
Quiescent Device Current	I _{DD}	V _{IN} = V _{SS} , V _{DD} *	5	—	0.25	—	0.001	0.25	—	7.5	μA	
			10	—	0.5	—	0.001	0.5	—	15		
			15	—	1.0	—	0.002	1.0	—	30		

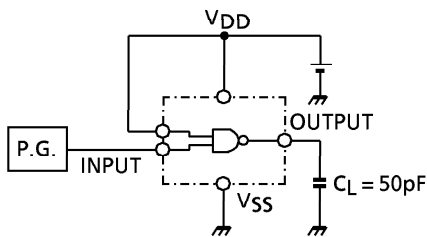
* All valid input combinations.

DYNAMIC ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$, $V_{SS} = 0\text{V}$, $C_L = 50\text{pF}$)

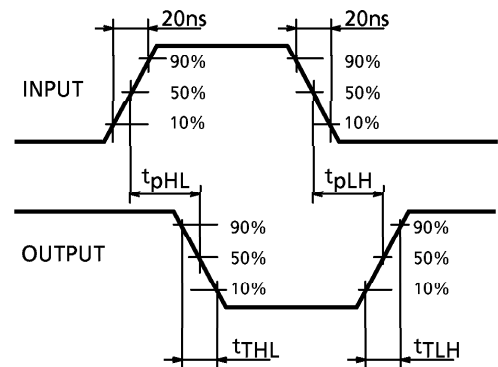
CHARACTERISTIC	SYMBOL	TEST CONDITION	V_{DD} (V)	MIN.	TYP.	MAX.	UNIT
Output Transition Time (Low to High)	t_{TLH}	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output Transition Time (High to Low)	t_{THL}	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Propagation Delay Time	t_{pLH}	—	5	—	65	200	ns
			10	—	30	100	
			15	—	25	80	
Propagation Delay Time	t_{pHL}	—	5	—	65	200	ns
			10	—	30	100	
			15	—	25	80	
Input Capacitance	C_{IN}	—	—	5	7.5	pF	

CIRCUIT AND WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS

TEST CIRCUIT



WAVEFORM



PACKAGE DIMENSIONS
SSOP5-P-0.95

Unit : mm



Weight : 0.016g (Typ.)

RESTRICTIONS ON PRODUCT USE

000707EBA

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